

Freeform Search

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Term:	<div style="border: 1px solid black; padding: 2px;"> L17 and (shutting off) </div>
Display:	<input type="text" value="50"/> Documents in Display Format: <input type="text" value="-"/> Starting with Number <input type="text" value="1"/>
Generate:	<input type="radio"/> Hit List <input checked="" type="radio"/> Hit Count <input type="radio"/> Side by Side <input type="radio"/> Image

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DATE: Monday, April 12, 2004 [Printable Copy](#) [Create Case](#)

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side by side

Hit Count Set Name

result set

DB=PGPB,USPT; PLUR=YES; OP=ADJ

<u>L18</u>	L17 and (shutting off)	1	<u>L18</u>
<u>L17</u>	09/819612	1	<u>L17</u>
<u>L16</u>	L15 and @ad<20000101	22	<u>L16</u>
<u>L15</u>	L8 and backup	64	<u>L15</u>
<u>L14</u>	L13 and @ad<20010301	11	<u>L14</u>
<u>L13</u>	L8 and (backup near3 server)	18	<u>L13</u>
<u>L12</u>	L11 and 345/\$.ccls.	5	<u>L12</u>
<u>L11</u>	L9 and 705/\$.ccls.	158	<u>L11</u>
<u>L10</u>	L9 and 707/\$.ccls.	36	<u>L10</u>
<u>L9</u>	virtual store	311	<u>L9</u>
<u>L8</u>	production management	933	<u>L8</u>
<u>L7</u>	L6 and server	18	<u>L7</u>
<u>L6</u>	L5 and @ad<20010301	22	<u>L6</u>
<u>L5</u>	L4 and (replicat\$3 near3 trigger)	25	<u>L5</u>
<u>L4</u>	L3 and backup	32910	<u>L4</u>
<u>L3</u>	product\$3 or manufactur\$3	2377465	<u>L3</u>

<u>L2</u>	L1 and product\$3	0	<u>L2</u>
<u>L1</u>	5758067.pn. or 6367029.pn.	2	<u>L1</u>

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Search Results for: **[replication trigger]**Found **1** of **130,565** searched.

Search within Results

[> Advanced Search](#)[> Search Help/Tips](#)**Sort by:** Title Publication Publication Date Score

Binder

Results 1 - 1 of 1 short listing**1** Update propagation strategies to improve freshness in lazy master 77%

replicated databases

Esther Pacitti , Eric Simon

The VLDB Journal — The International Journal on Very Large Data Bases February 2000

Volume 8 Issue 3-4

Many distributed database applications need to replicate data to improve data availability and query response time. The two-phase commit protocol guarantees mutual consistency of replicated data but does not provide good performance. Lazy replication has been used as an alternative solution in several types of applications such as on-line financial transactions and telecommunication systems. In this case, mutual consistency is relaxed and the concept of freshness is used to measure the deviation ...

Results 1 - 1 of 1 short listing

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